Search	Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/699,659	HSIEH CHEN, YI MEI
Examiner	Art Unit
Lenwood Faulcon, Jr.	3762

	SEARCHED				
Class	Subclass	Date	Examiner		
600	509, 536	5/17/2006	LF		
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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